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BIB DATA SHEET

CONFIRMATION NO. 6227

10/736,386	SERIAL NUMI	MBER FILING or 371(c)				CLASS	GROUP ART UNIT			ATTORNEY DOCKET			
APPLICANTS Bruce Whitefield, Camas, WA; David Abercrombie, Gresham, OR; ***CONTINUING DATA**** ***FOREIGN APPLICATIONS*** ***IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 03/24/2004 Foreign Priority caimed	10/736,386					703	2128						
Bruce Whitefield, Camas, WA; David Abercrombie, Gresham, OR; ***CONTINUING DATA********* ***FOREIGN APPLICATIONS**** ***IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 03/24/2004 Foreign Priority claimed			RUL	E									
** FOREIGN APPLICATIONS *** **** IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** (03/24/2004 Foreign Priority calmed	Bruce Whitefield, Camas, WA;												
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SSUSC 119(a-d) conditions met	** IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 03/24/2004												
Acknowledged Examerer's Signature Inneals WA 2 21 1 ADDRESS James R. Foley Trexler, Bushnell, Giangiorgi, Blackstone & Marr, 105 West Adams Street 36th Floor Chicago, IL 60603 UNITED STATES TITLE Method for calculating high-resolution wafer parameter profiles FILING FEE RECEIVED 788 FILING FEE RECEIVED No to charge/credit DEPOSIT ACCOUNT No to r following: All Fees	35 USC 119(a-d) conditions met ☐ Yes ☑ No ☐ Met after Allowance												
James R. Foley Trexler, Bushnell, Giangiorgi, Blackstone & Marr, 105 West Adams Street 36th Floor Chicago, IL 60603 UNITED STATES TITLE Method for calculating high-resolution wafer parameter profiles FILING FEE RECEIVED 788 FEES: Authority has been given in Paper No to charge/credit DEPOSIT ACCOUNT No for following: All Fees In 1.16 Fees (Fliting) 1.17 Fees (Processing Ext. of time) 1.18 Fees (Issue) Other						WA		2	21		1		
Trexler, Bushnell, Giangiorgi, Blackstone & Marr, 105 West Adams Street 36th Floor Chicago, IL 60603 UNITED STATES TITLE Method for calculating high-resolution wafer parameter profiles FILING FEE RECEIVED 788 FEES: Authority has been given in Paper No to charge/credit DEPOSIT ACCOUNT No for following: Q All Fees Q All	ADDRESS	ADDRESS											
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